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USB C type series
connectors
Product Specification

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Approved/Date	Checked/Date	Written/Date
2024/01/05	2024/01/05	2024/01/05

1.0 Scope : This specification covers the requirements for product performance and test methods of USB C TYPE Series Connectors of the part numbers specified as bellow.

Product shall be of the design, construction and physical dimensions specified in the applicable product drawing.

2.0 Rating:

2.1 Current Rating: VBUS pins(A4,B4,A9 and B9)&GND pins(A1,B1,B12 and A12) 5.0A(1.25A /Pin)

Other pins 0.25A/Pin

operatin g:-30°C to +80°C:

Humidity: 90% Rh max.

3.0 Test Condition:

All tests shall be performed as bellow conditions unless otherwise specified.

3.1 Temperature range : $+15^{\circ}$ C to $+35^{\circ}$ C

3.2 Humidity range: 90% Rh max

4.0 Test Methods and Requirements:

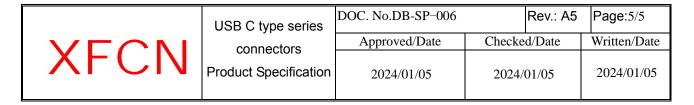
4.1 Examination of product:

Item	Test Description	Test Methods	Requirement				
4.1.1 E	xamination of	EIA 364-18	1).Outward appearance shall be				
	product (Outward	Shall be confirmed with eyes in	good without such injurious problem				
	Appearance	accordance with each drawing.	2).Structure shall be meet the design				
	Structure)	Shall be confirmed by using proper	and dimensional requirements of				
		measuring instruments.	drawing.				
4.2	Electrical Performan	ce:					
Item	Test Description	Test Methods	Requirement				
4.2.1	Low Level Contact	EIA 364-23 (or MIL-STD-1344A,					
	Resistance	Method 3002.1, Test Condition B)					
		30m Ω (Max) when measured at					
		20mv(max) open circuit at	40 mΩ Maxi mum				
		100mA.Contact resistance below 40 m					
		Ω after 10000 insertion/extraction					
		cycles at a maximum rate of 500 cycles					
		per hour					

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4001									
4.2.2 Ir	sulatio n Resistance	(or MIL-STD-202F, Met	had 202 Tast						
		Condition B)	110d 302, 1est	100 M Ω Mini	mum				
		/D.C 500 V is applied I	netween	TOO WILL IVIIIII	illulli				
		adjacent congacts and							
		resistance is measured							
4.2.3 D	iele ctric	EIA 364-20		There shall be	no shortci	ircuiting and			
	Withstanding Voltage	(or MIL-STD-202F, Met	1004 - 1			100 V R.M.S			
	3 0	Condition B)		for 1 minute.	ned di 710	100 V 11.IVI.O			
		Test between adjacent		ioi i illiliate.					
		mated and unmated co							
		assemblies.							
		The object of this test	procedure is to						
		detail a test method to	prove that a						
		MICRO USB connector	can operate						
		safely at its rated voltag	e and withstand						
		momentary over potent	ials due to						
		switching, surges and/o	r other similar						
		phenomena.							
4.3 Me	echanical Performan								
Item	Test Description	Test Metho	ods	R	Requireme	nt			
4.3.1 I	nse rtion Force	EIA 364-13							
		The insertion force test			0.5~2.0kg	Ī			
		a maximum rate of			U.5~2.UKg1				
4.3.2 F	Extraction Force	a maximum rate of EIA 364-13	12.5mm/min.						
4.3.2	Extraction Force	a maximum rate of EIA 364-13 The extraction force te	12.5mm/min.		0.5~2.0kg				
		a maximum rate of EIA 364-13 The extraction force te at a maximum rate of	12.5mm/min.		0.8~2.0kg	f			
	Extraction Force urability	a maximum rate of EIA 364-13 The extraction force te at a maximum rate of EIA 364-09	12.5mm/min. st shall be done r 12.5mm/min.	1) No flashov	0.8~2.0kg	f			
		a maximum rate of EIA 364-13 The extraction force te at a maximum rate of EIA 364-09 Mate and unmate Con	12.5mm/min. st shall be done r 12.5mm/min. nector	No flashove breakdown	0.8~2.0kg ver or insu n	f			
		a maximum rate of EIA 364-13 The extraction force te at a maximum rate of EIA 364-09 Mate and unmate Con assemblies for 10000 c	12.5mm/min. st shall be done r 12.5mm/min. nector ycles at	No flashove breakdown Extraction	0.8~2.0kgt ver or insun n Force:	f lation			
		a maximum rate of EIA 364-13 The extraction force te at a maximum rate of EIA 364-09 Mate and unmate Con assemblies for 10000 comaximum rated of 500 comaxim	12.5mm/min. st shall be done r 12.5mm/min. nector ycles at cycles per hour.	1) No flashow breakdow 2) Extraction 1-1000cyc	0.8~2.0kg ver or insu n Force: cles: 0.8~2	f lation .0kgf			
		a maximum rate of EIA 364-13 The extraction force te at a maximum rate of EIA 364-09 Mate and unmate Con assemblies for 10000 c	st shall be done r 12.5mm/min. nector ycles at cycles per hour.	1) No flashove breakdown 2) Extraction 1-1000cyc 1000~100	0.8~2.0kg ver or insu n Force: cles: 0.8~2 00cycles:	f lation .0kgf 0.6~2.0kgf			
4.3.3 D	urability	a maximum rate of EIA 364-13 The extraction force te at a maximum rate of EIA 364-09 Mate and unmate Con assemblies for 10000 c maximum rated of 500 Flip Interval: Every 250	st shall be done r 12.5mm/min. nector ycles at cycles per hour.	1) No flashow breakdow 2) Extraction 1-1000cyc	0.8~2.0kgt ver or insu n Force: cles: 0.8~2 00cycles: sistance: M	f lation $0 \cdot 0 \cdot 0 \cdot 0 \cdot 0 \cdot 0 \cdot 0 \cdot 0$ lax.50m Ω			
4.3.3 D		a maximum rate of EIA 364-13 The extraction force te at a maximum rate of EIA 364-09 Mate and unmate Con assemblies for 10000 c maximum rated of 500 c Flip Interval: Every 250 EIA-364-27B	st shall be done r 12.5mm/min. nector ycles at cycles per hour.	1) No flashove breakdown 2) Extraction 1-1000cyc 1000~100 3)Contact Res	0.8~2.0kgt ver or insu n Force: cles: 0.8~2 00cycles: sistance: M	f lation $0 \cdot 0 \cdot 0 \cdot 0 \cdot 0 \cdot 0 \cdot 0 \cdot 0$ lax.50m Ω			
4.3.3 D	urability	a maximum rate of EIA 364-13 The extraction force te at a maximum rate of EIA 364-09 Mate and unmate Con assemblies for 10000 c maximum rated of 500 Flip Interval: Every 250 EIA-364-27B Subject mated connected	st shall be done r 12.5mm/min. nector ycles at cycles per hour. 00 cycles	1) No flashove breakdown 2) Extraction 1-1000cyc 1000~100 3)Contact Res	0.8~2.0kgt ver or insu n Force: cles: 0.8~2 00cycles: sistance: M	f lation $0 \cdot 0 \cdot 0 \cdot 0 \cdot 0 \cdot 0 \cdot 0 \cdot 0$ lax.50m Ω			
4.3.3 D	urability	a maximum rate of EIA 364-13 The extraction force te at a maximum rate of EIA 364-09 Mate and unmate Con assemblies for 10000 c maximum rated of 500 c Flip Interval: Every 250 EIA-364-27B	at shall be done or 12.5mm/min. nector ycles at cycles per hour. Ou cycles or to 50G's of 11msec	1) No flashove breakdown 2) Extraction 1-1000cyc 1000~100 3)Contact Res No discontinuit long duration. S	0.8~2.0kgt ver or insu n Force: cles: 0.8~2 00cycles: sistance: M	f lation $0 \cdot 0 \cdot 0 \cdot 0 \cdot 0 \cdot 0 \cdot 0 \cdot 0$ lax.50m Ω			
4.3.3 D	urability	a maximum rate of EIA 364-13 The extraction force te at a maximum rate of EIA 364-09 Mate and unmate Con assemblies for 10000 c maximum rated of 500 Flip Interval: Every 250 EIA-364-27B Subject mated connecte half-sine shock pulses of	at shall be done or 12.5mm/min. nector ycles at cycles per hour. Ou cycles or to 50G's of 11msec on each direction	1) No flashove breakdown 2) Extraction 1-1000cyc 1000~100 3)Contact Res No discontinuit long duration. S	0.8~2.0kgt ver or insu n Force: cles: 0.8~2 00cycles: sistance: M	f lation $0 \cdot 0 \cdot 0 \cdot 0 \cdot 0 \cdot 0 \cdot 0 \cdot 0$ lax.50m Ω			
4.3.3 D	urability	a maximum rate of EIA 364-13 The extraction force te at a maximum rate of EIA 364-09 Mate and unmate Con assemblies for 10000 c maximum rated of 500 c Flip Interval: Every 250 EIA-364-27B Subject mated connecte half-sine shock pulses of duration. Three shocks	at shall be done or 12.5mm/min. nector ycles at cycles per hour. Ou cycles or to 50G's of 11msec on each direction	1) No flashove breakdown 2) Extraction 1-1000cyc 1000~100 3)Contact Res No discontinuit long duration. S	0.8~2.0kgt ver or insu n Force: cles: 0.8~2 00cycles: sistance: M	f lation .0kgf 0.6~2.0kgf lax.50mΩ			

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\/		connectors	Approved/Date	e	Checked/Date		Written/Date			
X	FCN	Product Specification	2024/01/05		2024/0	01/05	2024/01/05			
		shocks								
4.3.5	Vibration	EIA-364-28	continuities of 1 microsecond or							
		Subject mated connect	ors to	long dı	aration. S	ee note				
		10~55~10Hz traversed	in 1 minute at							
		1.52mm amplitude 2 ho								
		mutually perpendicular	planes.							
4.4 Er	vironmental Perform	iance:								
Item	Test Description	Test M	lethods			Require	ment			
4.4.1 T	hermal Shock	EIA 364-32, Test Cond	lition I,		1).Shall	meet visu	ıal			
		(or MIL-202F, Method	107G Condition A	٨.)	requirer	ment, show	v no physical			
		•	•	i	damage	€.				
		between –30°C to +80°	℃.		2).Shall	meet requ	uirements of			
		The object of this test	is to determine th	e	additional tests as specified in					
		resistance of a micro u	sb connector to		test sec	quence in S	Section 5			
		exposure at extremes of	of high and low							
		temperatures and to the	e shock of alterna	ite						
		exposures to these ext	remes, simulating	the						
		wrost case conditions f	or storage,							
4.4.2 H	umi dity	·			1).Shall	meet visu	ıal			
		(or MIL-202F, Method 103B Test Condition B.)								
		-		6	damage.					
(or MIL-202F, Method 107G Condition A.) Subject mated connectors to ten cycles between −30°C to +80°C. The object of this test is to determine the resistance of a micro usb connector to exposure at extremes of high and low temperatures and to the shock of alternate exposures to these extremes, simulating the wrost case conditions for storage, transportation and application. 4.4.2 Humi dity EIA 364-31, Test Condition A Method III, (or MIL-202F, Method 103B Test Condition B.) Subject mated connectors to 168 Hours (seven complete cycles) The object of this test procedure is to detail a additional te										
		-					·			
					test sec	quence in S	Section 5			
			-	fects						
4.4.3 S	alt Spray	·	d 101D, Test		'					
			-t t- 0.4 !	-1 05			v no physical			
		-		at 35	_		dinama t C			
		⊜ with 5%-Salt-solutio	on concentration.		,	-				
	The object of this test is to determine the resistance of a micro usb connector to exposure at extremes of high and low temperatures and to the shock of alternate exposures to these extremes, simulating the wrost case conditions for storage, transportation and application. Humi dity EIA 364-31, Test Condition A Method III, (or MIL-202F, Method 103B Test Condition B.) Subject mated connectors to 168 Hours (seven complete cycles) The object of this test procedure is to detail a standard method for the evaluation of the properties of materials used in Micro USB connectors as these influenced by the effects of high humidity and heat.									
					iest sec	querice in s	Section 5			

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4.4.4 T	emperature Life	EIA 364-17 Test Cond	ition 3 Method A	,	1).Shall	l meet visu	al
		Subject mated connec	ctors to temperatu	re life	require	ment, shov	v no physical
		at 80°C for 250hours			damage	Э.	
					2).Shall	l meet requ	uirements of
					addition	nal tests as	specified in
					test sec	quence in S	Section 5
4.4 En	vironmental Performa						
Item	Test Description	Test Meth				Requiremen	
4.4.5 S	olderability	EIA 364-52				f the portio	
		After one hour steam	0 0				5% covered
		The object of test prod				er coating,	as specified in
		a unfirm test methods f		Categ	ory 2.		
		micro usb connectors s	_				
		test procedure containe					
		the solder dip technique					
		intended to test or eval	·				
		solder eyelet, other har					
4460	e sistance to	or SMT type termination 1) for WAVE SOLDE F		1) No	machar	nigal dafaa	t on housing
4.4.0 N		MIL-STD-202F, Method	,	er parts.	ilcai delec	t off flousing	
	Coldening Treat	Condition B.	Or Oth	ci parts.			
			0°ℂ, 60 Seconds				
			60 ± 5 °C				
		•	-				
		Immersion duration : 10					
		2) for REFLOW SOLDE					
		EIAJ RCX-0101/102					
		Pre-heat : 150(Mir	, , , ,				
			80 Seconds				
		•	60 ± 5 ℃				
		Immersion duration : 10	0~40 sec.				
		Z-4C*/s TEMP Pre-heat:180-200°C (120sec Min) 2-4C*/sec TIM	220°C (60sec Min)				



Test Group (a)			Sample Groups												
Test Item	Test Description		Α		В		С	D)	Е		FG			
4.1.1	Examination of product	1,	13	1,	5	1,	8	1, 3	3	1, 5	1	3	1	6	
4.2.1	Low Level Contact Resistance	2,	10	2,	4					2, 4			2	5	
4.2.2 Insul	atio n Resistance	3	11			2	,6								
4.2.3	Dielectric Withstanding Voltage	4	12			3	,7								
4.3.1	Insertion Force	5	8												
4.3 2	Extraction Force	6	9												
4.3 3	Durability	7													
4.3.4	Mechanical Shock												3		
4.3.5	Vibration										4	4			
4.4.1	Thermal Shock					5									
4.4.2	Humidity					4									
4.4.3	Salt Spray			3											
4.4.4	Temperature Life(see note c)									3					
4.4.5	Solderability					2									
4.4.6	Resistance to Soldering Heat										2				
Num	nber of Test Samples (Minimum)		5		5		5 5			5		5 5			

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